

[REDACTED]

James D. Ewart

2617

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

[illegible]

Search Notes (continued)

Application/Control No.

10/697,755

Examiner

James D. Ewart

Applicant(s)/Patent under
Reexamination

NOBUSAWA ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
348	14.02	5/17/2006	JDE
	14.04		
	14.05		
	552		
	553		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR